

**Notice of References Cited**

Application/Control No.

09/323,650

Applicant(s)/Patent Under  
Reexamination  
CHUBB ET AL.

Examiner

Lydia M. De Jesús

Art Unit

2859

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*		Document Number	Date	Name	Classification	
		Country Code-Number-Kind Code	MM-YYYY			
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	B	US-6045259-	04-2000	Djeu	374	161
	C	US-4794619-	12-1988	Tregay	374	130
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		Country Code-Number-Kind Code	MM-YYYY				
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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